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Noise Performance of the HEC at SLHC (very preliminary estimates)

Meeting at MPI on “HEC cold electronics”
16-th of April, 2007

Content

- Introduction
- HEC structure
- Shaping functions
- Noise versus peaking time
- Next steps



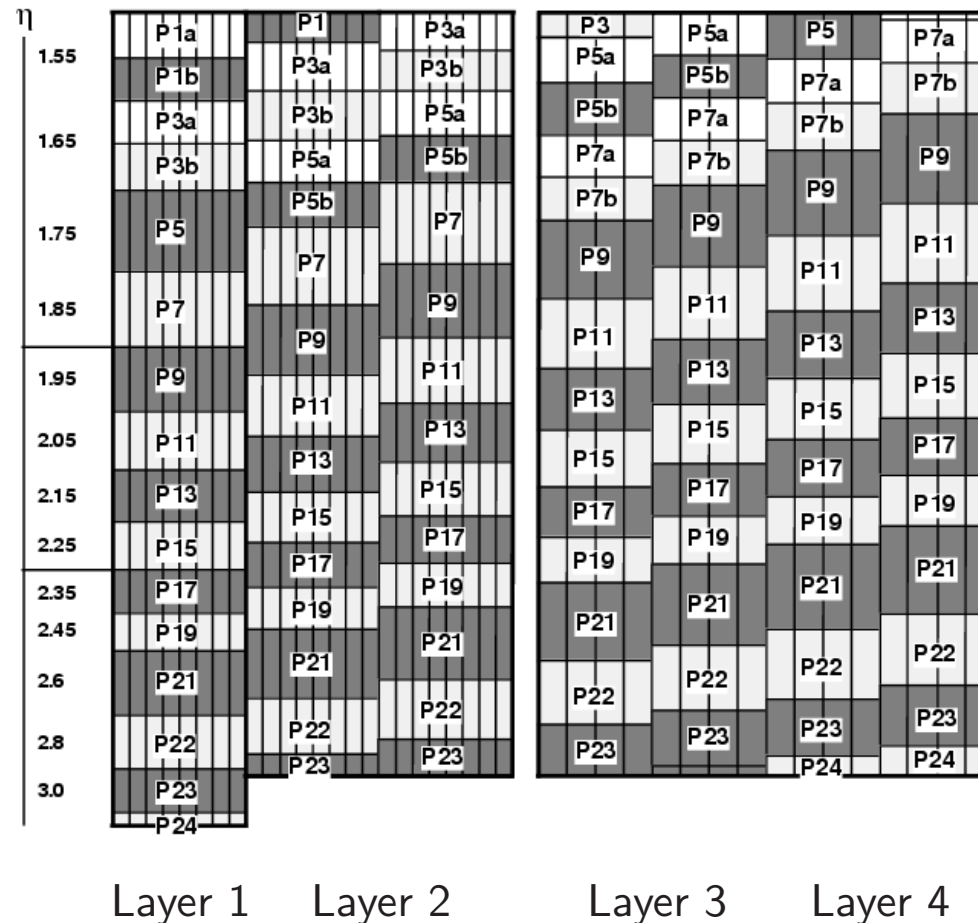
Introduction

- Two sources of noise in calorimeter channels:
 - electronics
 - pileup of minimum bias events, happened in the neighbouring bunch crossings
- Different behaviour of noise as a function of the peaking time:
 - electronic noise σ_{EL} decreasing
 - pileup noise σ_{PU} increasing
- Current design of HEC electronics is optimised for LHC luminosities:
 - low $L = 10^{33} \text{ cm}^{-2}\text{s}^{-1}$
 - high $L = 10^{34} \text{ cm}^{-2}\text{s}^{-1}$
- Super LHC luminosity ($L = 10^{35} \text{ cm}^{-2}\text{s}^{-1}$) requires new electronics
- This talk: first attempt to estimate total noise in HEC channels at SLHC
- **Old programmes** (used for HEC optimisation in 1997-1999) are applied for present calculations



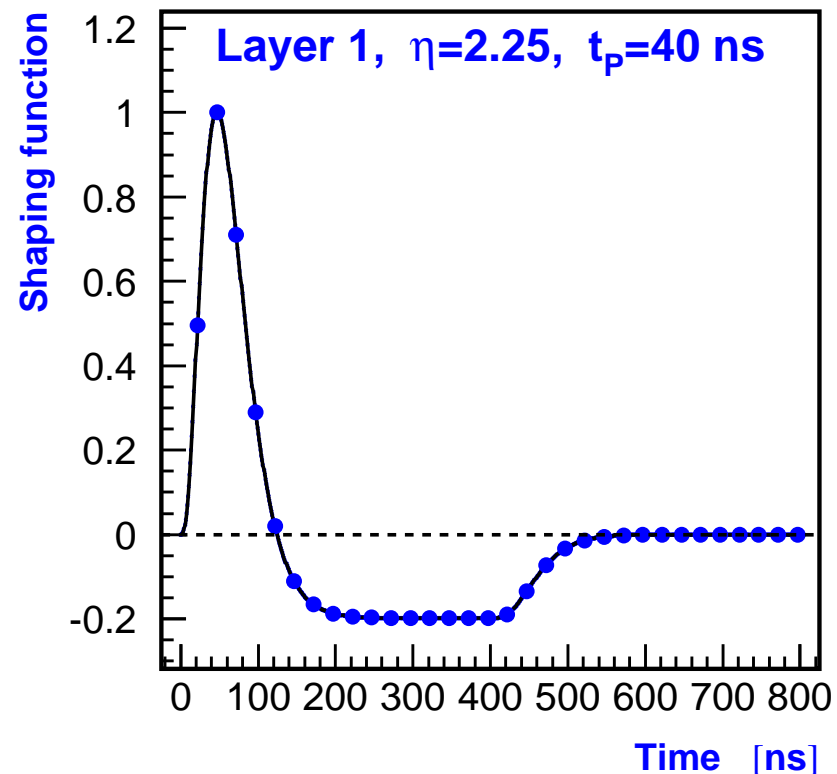
Channels in the HEC

- Hadronic end-cap calorimeter:
 - 2 front and 2 rear wheels
 - 32 modules in a wheel
- 5632 channels in total
- 51 different types of channels (azimuthal symmetry)
 - 14 pseudorapidity bins
 - 4 longitudinal layers
 - detector capacitance
 - cable length
 - number of preamplifiers



Shaping Functions

- FORTRAN-based programme from L. Kurchaninov and D. Salihagić
- Shaping function f_{SH} :
 - shaping time t_{SH}
 - detector capacitance C_D
- Peaking time t_P as a rise time of a shaping function from 5 to 100 %
- Set of shaping functions
 - 51 HEC channels
 - 19 values of the peaking time: from 20 to 110 ns

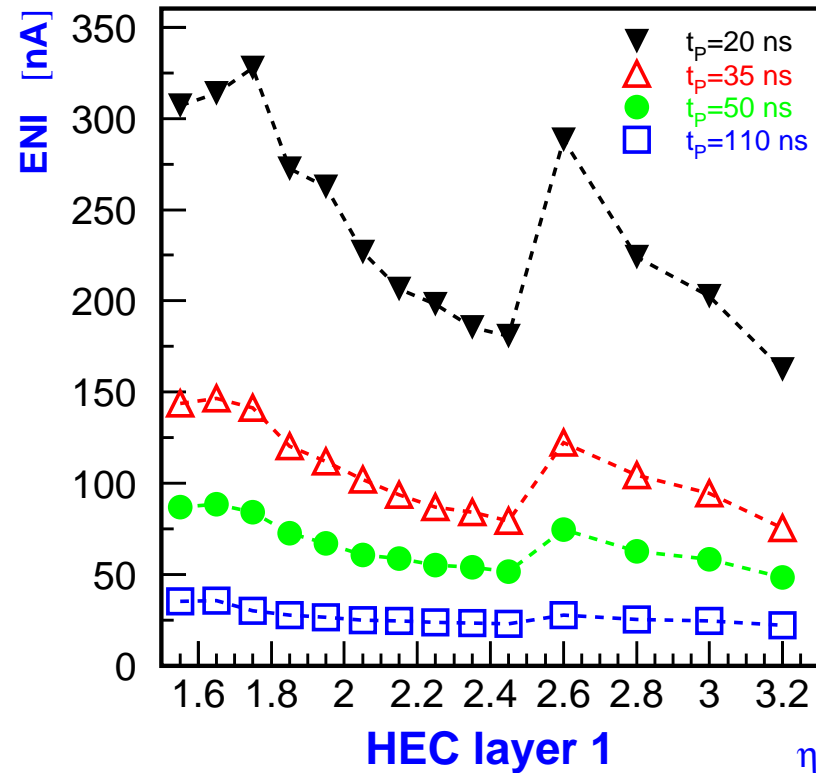


Electronic Noise

- Code from L. Kurchaninov
- Equivalent noise current (ENI)
 - shaping time t_{SH}
 - detector capacitance C_D
 - cable length
 - number of preamplifiers
- Electronic noise at the **visible energy scale**

$$\sigma_{EL} = ENI/C_0,$$

where $C_0 = 7135 \text{ nA/GeV}$

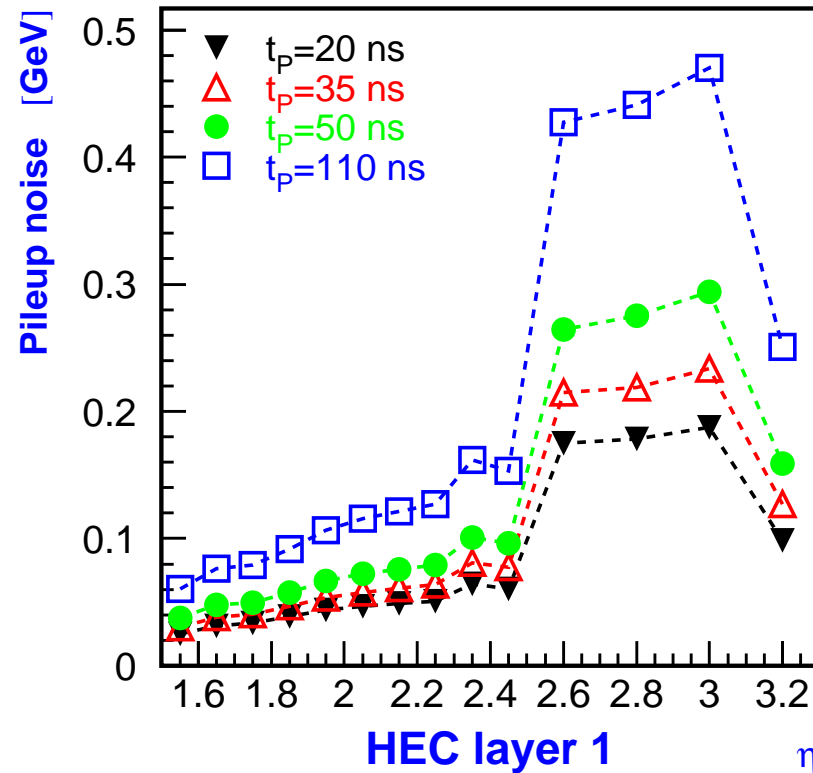


Pileup Noise

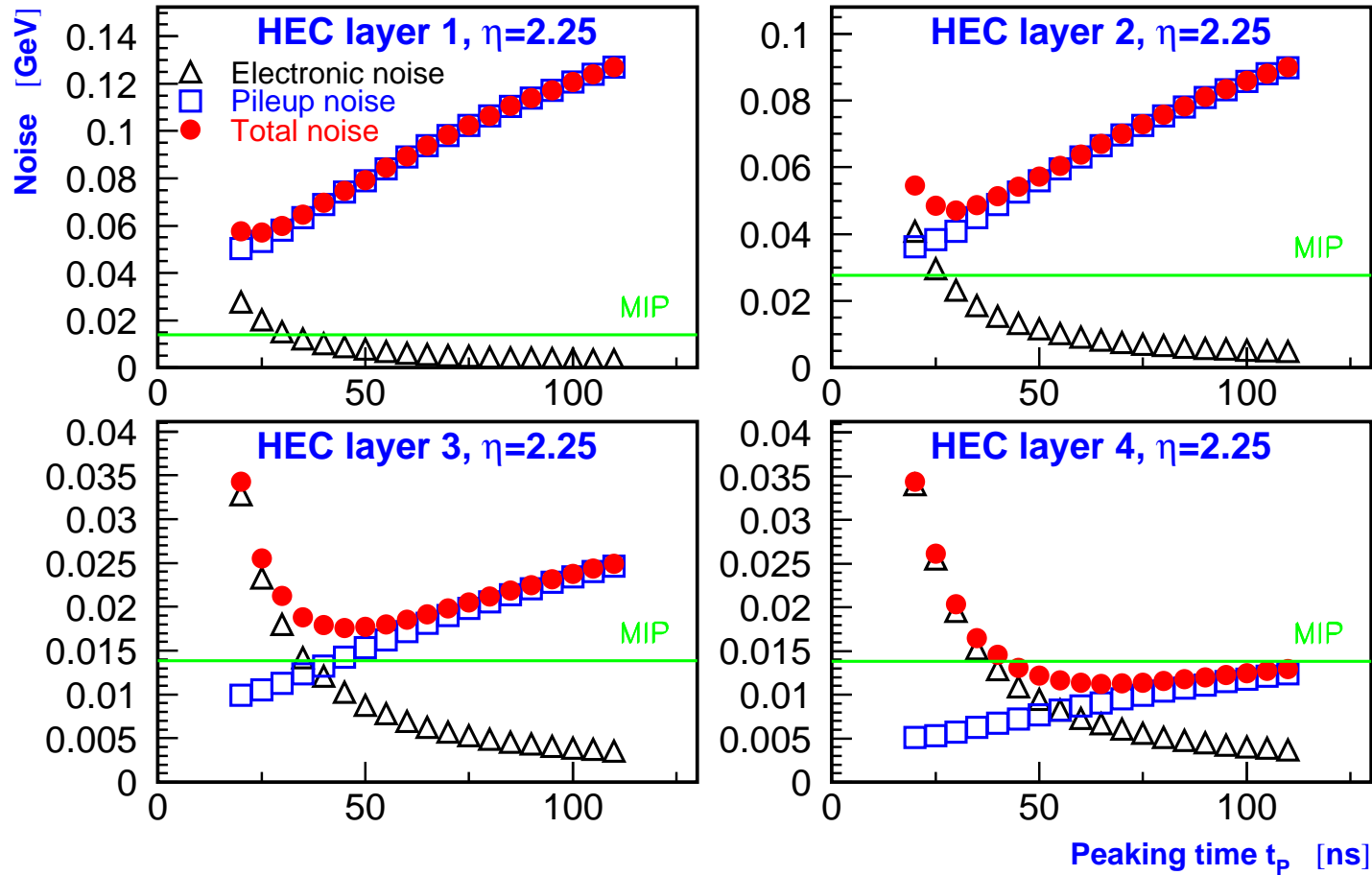
- 2871 minimum bias events, fully simulated with the version 96_12 (calorimeter TDRs)
- Pileup of N_{MB} in average (Poisson distributed) minimum bias events per bunch crossing ($N_{MB} = 230$ at SLHC)
- R.M.S. of distribution of visible energy in one channel in one bunch crossing σ_{BX} — pileup noise for the infinitely fast detector ($t_P=0$)
- “Shaping integral”:

$$S_{int} = \sqrt{\sum_{25ns} f_{SH}^2}$$
- Pileup noise — result of convolution with a shaping function:

$$\sigma_{PU} = \sigma_{BX} \times S_{int}$$



Noise versus Peaking Time

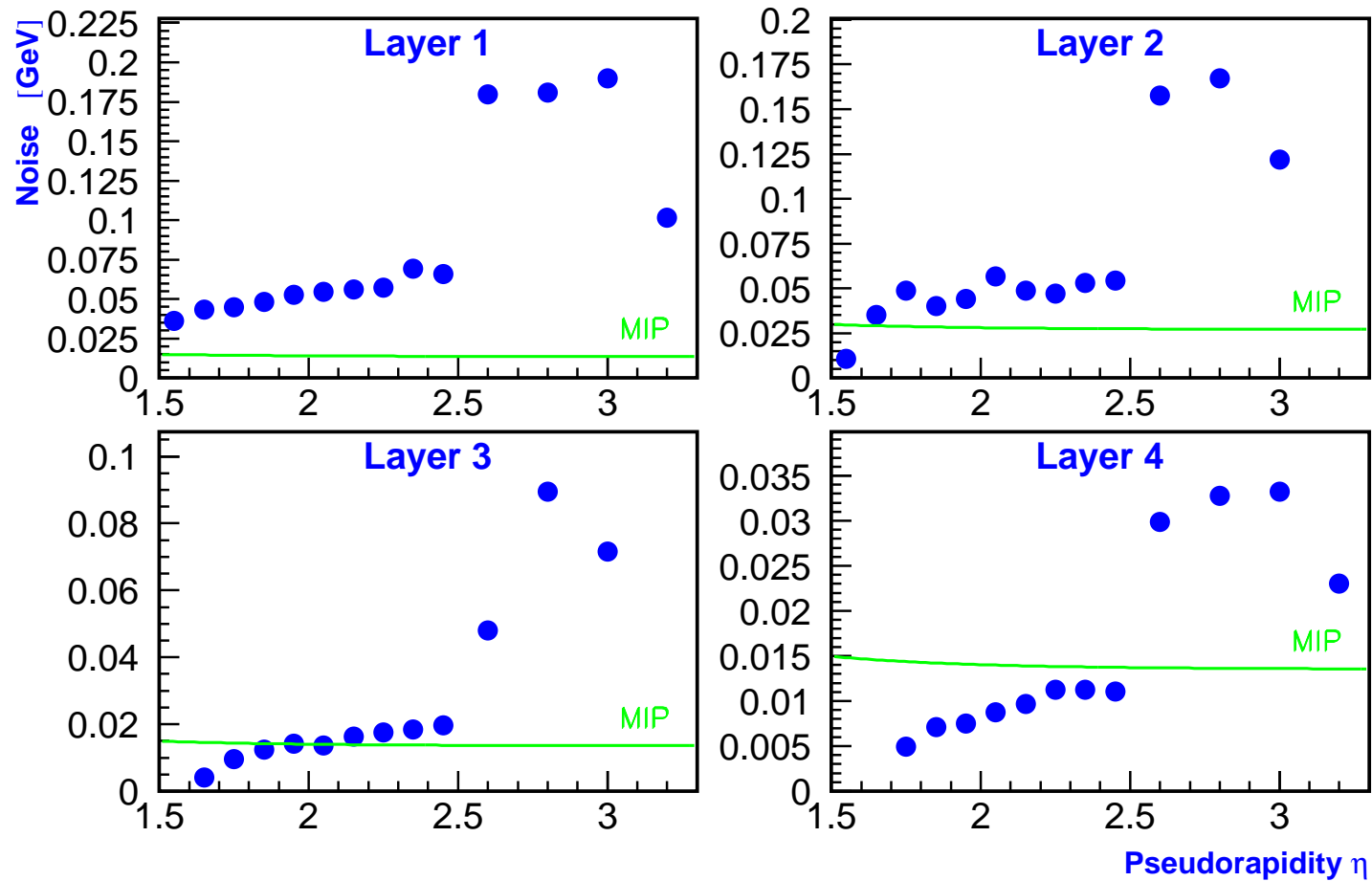


$$\text{Total noise } \sigma_{TOT} = \sqrt{\sigma_{EL}^2 + \sigma_{PU}^2}$$



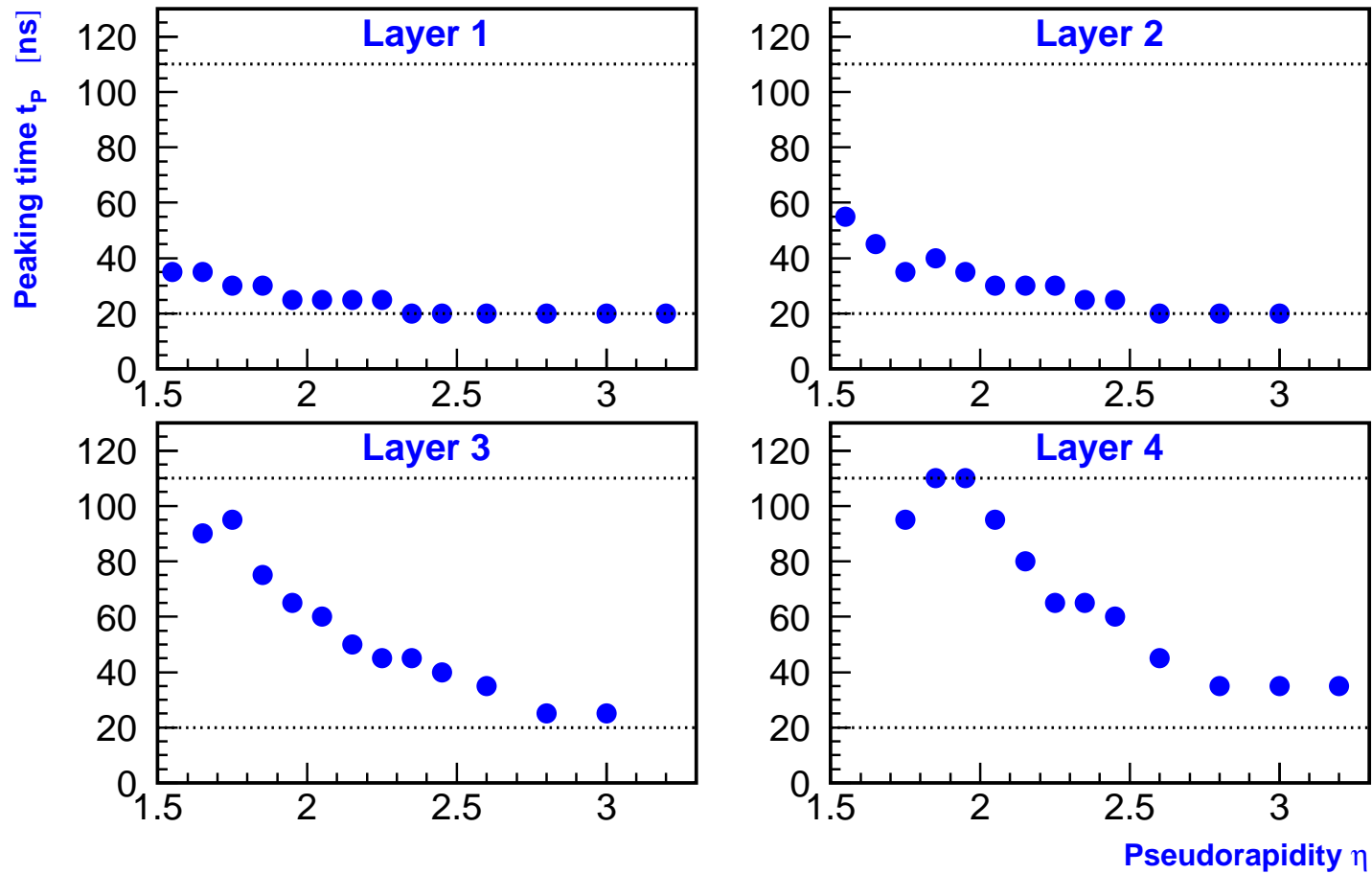
Noise versus Peaking time

Minimal total noise



Noise versus Peaking time

Peaking time corresponding to minimal total noise



Next Steps?

1. Old model of HEC electronics chain \Rightarrow
Complete model (L. Kurchaninov, ATLAS HEC Note-109, 2001)
 - calculations with MCAD under Windows
 - different peaking times
 - other types of preamplifiers, shapers, etc.
2. Measurements in one time sampling \Rightarrow
Measurements in five time samplings and optimal weighting
 - other schemes (not five samplings, not every sampling, etc.)
3. Old simulations of minimum bias events \Rightarrow
Latest simulations
 - another structure of HEC channels (longitudinal segmentation, transverse granularity) ?

